

10091226
02/28/02

PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

10091226

APPL NUM 10091226	FILING DATE 02/28/2002	CLASS 073 433	SURCLASS 105	GAU 2812	EXAMINER Raeu's
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**APPLICANTS: Vandervorst Wilfried; Eyben Pierre;

**CONTINUING DATA VERIFIED:

THIS APPLN CLAIMS BENEFIT OF 60/272,249 02/28/2001

** FOREIGN APPLICATIONS VERIFIED:

PG-PUB DO NOT PUBLISH ☐

RESCIND ☐

Foreign priority claimed

☐ yes ☒ no

35 USC 119 conditions met

☐ yes ☒ no

Verified and Acknowledged Examiners's initials

ATTORNEY DOCKET NO

IMEC239.001AUS

TITLE : Method and apparatus for performing atomic force microscopy measurements

U.S. DEPT. OF COMM./PAT. & TM.-PTO-435L (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	Print Claim for O.G
Assistant Examiner		DRAWING	
		Sheets Drwg.	Figs. Drwg.
Amount Due		Print Fig.	
Date Paid			
Primary Examiner		Application Examiner	
PREPARED FOR ISSUE			
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